

2N3304 (SILICON)



PNP silicon annular transistor designed for low-level, high-speed switching applications.

CASE 22 (TO-18)

Collector connected to case

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	6.0	Vdc
Collector-Base Voltage	V_{CB}	6.0	Vdc
Emitter-Base Voltage	V_{EB}	4.0	Vdc
Total Device Dissipation @ $T_A = 25^{\circ}\text{C}$ Derate above 25°C	P_D	300 1.72	mW mW/ $^{\circ}\text{C}$
Total Device Dissipation @ $T_C = 100^{\circ}\text{C}$ Derate above 100°C	P_D	500 5.0	mW mW/ $^{\circ}\text{C}$
Operating & Storage Junction Temperature Range	T_J, T_{stg}	-65 to +200	$^{\circ}\text{C}$

2N3304 (continued)

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector-Emitter Sustaining Voltage (1) ($I_C = 10 \text{ mAdc}$, $I_B = 0$)	$BV_{CEO(sus)}$	6.0	—	Vdc
Collector-Emitter Breakdown Voltage ($I_C = 100 \mu\text{A}$, $V_{BE} = 0$)	BV_{CES}	6.0	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 100 \mu\text{A}$, $I_E = 0$)	BV_{CBO}	6.0	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 100 \mu\text{A}$, $I_C = 0$)	BV_{EBO}	4.0	—	Vdc
Collector-Cutoff Current ($V_{CE} = 3 \text{ Vdc}$, $V_{BE} = 0$) ($V_{CE} = 3 \text{ Vdc}$, $V_{BE} = 0$, $T_A = +125^\circ\text{C}$)	I_{CES}	—	0.01 10	μA dc
Base Current ($V_{CE} = 3 \text{ Vdc}$, $V_{BE} = 0$)	I_B	—	10	nA

ON CHARACTERISTICS

DC Current Gain (1) ($I_C = 1 \text{ mA}$, $V_{CE} = 0.5 \text{ Vdc}$) ($I_C = 10 \text{ mA}$, $V_{CE} = 0.3 \text{ Vdc}$, $T_A = -55^\circ\text{C}$) ($I_C = 10 \text{ mA}$, $V_{CE} = 0.3 \text{ Vdc}$) ($I_C = 50 \text{ mA}$, $V_{CE} = 1.0 \text{ Vdc}$)	h_{FE}	15 12 30 20	— — 120 —	—
Collector-Emitter Saturation Voltage ($I_C = 1 \text{ mA}$, $I_B = 0.1 \text{ mA}$) ($I_C = 10 \text{ mA}$, $I_B = 1 \text{ mA}$, $T_A = +125^\circ\text{C}$) ($I_C = 10 \text{ mA}$, $I_B = 1 \text{ mA}$) ($I_C = 50 \text{ mA}$, $I_B = 5 \text{ mA}$)	$V_{CE(sat)}$	— — — —	0.15 0.23 0.16 0.5	Vdc
Base-Emitter Saturation Voltage ($I_C = 1 \text{ mA}$, $I_B = 0.1 \text{ mA}$) ($I_C = 10 \text{ mA}$, $I_B = 1 \text{ mA}$) ($I_C = 50 \text{ mA}$, $I_B = 5 \text{ mA}$)	$V_{BE(sat)}$	0.7 0.8 —	0.8 1.0 1.5	Vdc

DYNAMIC CHARACTERISTICS

Current-Gain-Bandwidth Product ($I_C = 10 \text{ mA}$, $V_{CE} = 5 \text{ Vdc}$, $f = 100 \text{ MHz}$)	f_T	500	—	MHz
Output Capacitance ($V_{CB} = 5 \text{ Vdc}$, $I_E = 0$, $f = 140 \text{ kHz}$)	C_{ob}	—	3.5	pF
Input Capacitance ($V_{BE} = 0.5 \text{ Vdc}$, $I_C = 0$, $f = 140 \text{ kHz}$)	C_{ib}	—	3.5	pF
Turn-On Time (Figure 1) ($V_{CC} = 1.5 \text{ Vdc}$, $V_{BB} = 6 \text{ Vdc}$, $I_C = 10 \text{ mA}$, $I_{B1} = I_{B2} = 0.5 \text{ mA}$)	t_{on}	—	60	ns
Turn-Off Time (Figure 1) ($V_{CC} = 1.5 \text{ Vdc}$, $I_C = 10 \text{ mA}$, $I_{B1} = I_{B2} = 0.5 \text{ mA}$)	t_{off}	—	60	ns
Charge-Storage Time (Figure 2) ($I_C = 10 \text{ mA}$, $V_{CC} = 3 \text{ Vdc}$, $I_{B1} = I_{B2} = 10 \text{ mA}$)	t_s	—	30	ns

(1) Pulse Test: Pulse Width = $300 \mu\text{s}$; Duty Cycle = 2%

FIGURE 1 — TURN-ON & TURN-OFF TIME TEST CIRCUIT

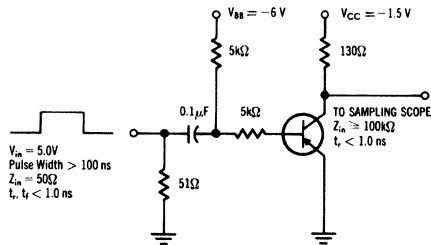


FIGURE 2 — CHARGE-STORAGE TIME TEST CIRCUIT

